

| | | | | |
|-----------------------------------|--|--------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination ARAO ET AL. | |
| | | Examiner Nadeem Iqbal | Art Unit 2114 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-7,028,231 B1 | 04-2006 | Tezuka, Hiroshi | 714/704 |
| * | B | US-6,487,686 B1 | 11-2002 | Yamazaki et al. | 714/703 |
| * | C | US-7,092,435 B2 | 08-2006 | Saruwatari, Eiji | 375/227 |
| * | D | US-4,800,562 | 01-1989 | Hicks, Gregory F. | 714/704 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.